



4-Channel/8-Channel Fault-Protected Analog Multiplexers

ADG508F/ADG509F

4" to 8" Transfer Evaluation Report

ADG508F/ADG509F 4" TO 8" TRANSFER EVALUATION SUMMARY

This document highlights the performance differences between the 4" and 8" Transfer for the ADG508F and ADG509F Fault Protected Analog Multiplexers.

There was no significant specification changes due to this transfer but some subtle changes are covered in this document. Latch-up, ESD classification, Power supply sequencing and Absolute maximum ratings evaluation were carried out without any issue.

This document is divided into 3 sections:

1. Datasheet specification changes from 4" to 8" process transfer

Table 1 outlines a datasheet specification comparison of 4" and 8" material.

2. ABSOLUTE MAXIMUM RATINGS

Tables 2 & 3 outline a comparison of the absolute maximum ratings between 4" and 8" processes.

3. TYPICAL PERFORMANCE CHARACTERISTICS

The TYPICAL PERFORMANCE CHARACTERISTICS section (Figures 1 to 24) compares typical plots of 4" and 8" material

ADG508F/ADG509F

TABLE OF CONTENTS

ADG508F/ADG509F 4" to 8" transfer Evaluation Summary	1	Dual Supply.....	3
Table of Contents	2	Absolute Maximum Ratings	5
Specification Changes from 4" to 8" Process Transfer	3	Typical Performance Characteristics	6

SPECIFICATION CHANGES FROM 4" TO 8" PROCESS TRANSFER

DUAL SUPPLY

$V_{DD} = +15 \text{ V} \pm 10\%$, $V_{SS} = -15 \text{ V} \pm 10\%$, GND = 0 V, unless otherwise noted.

Table 1.

Parameter	4" Version –40°C to +85°C		8" Version –40°C to +85°C		Unit	Test Conditions/Comments
	+25°C		+25°C			
ANALOG SWITCH						
Analog Signal Range						
R_{ON}	300	350	270	350	Ω typ	$-10 \text{ V} \leq V_s \leq +10 \text{ V}$, $I_s = 1 \text{ mA}$; $V_{DD} = +15 \text{ V} \pm 10\%$, $V_{SS} = -15 \text{ V} \pm 10\%$
R_{ON} Drift	0.6		0.6		%/°C typ	$-10 \text{ V} \leq V_s \leq +10 \text{ V}$, $I_s = 1 \text{ mA}$;
R_{ON} Match	5		2		% max	$V_{DD} = +15 \text{ V} \pm 5\%$, $V_{SS} = -15 \text{ V} \pm 5\%$ $V_s = 0 \text{ V}$, $I_s = 1 \text{ mA}$ $V_s = 0 \text{ V}$, $I_s = 1 \text{ mA}$
LEAKAGE CURRENTS						
Source OFF Leakage I_s (OFF)	±0.02		±0.02		nA typ	$V_D = \pm 10 \text{ V}$, $V_s = \mp 10 \text{ V}$;
Drain OFF Leakage I_D (OFF)	±1	±50	±1	±50	nA max	$V_D = \pm 10 \text{ V}$, $V_s = \mp 10 \text{ V}$;
ADG508F/ADG528F	±0.04		±0.04		nA typ	
ADG509F	±1	±60	±1	±60	nA max	
ADG509F	±1	±30	±1	±30	nA max	
Channel ON Leakage I_D , I_s (ON)	±0.04		±0.04		nA typ	$V_s = V_D = \pm 10 \text{ V}$;
ADG508F/ADG528F	±1	±60	±1	±60	nA max	
ADG509F	±1	±30	±1	±30	nA max	
FAULT						
Output Leakage Current (With Overvoltage)	±0.02		±0.02		nA typ	$V_s = \pm 33 \text{ V}$, $V_D = 0 \text{ V}$,
Input Leakage Current (With Overvoltage)	±2	±2	±2	±2	µA max	$V_s = \pm 25 \text{ V}$, $V_D = \mp 10 \text{ V}$,
Input Leakage Current (With Power Supplies OFF)	±0.005		±0.005		µA typ	$V_s = \pm 25 \text{ V}$, $V_D = V_{EN} = A0, A1, A2 = 0 \text{ V}$
INPUT CAPACITANCE	±2		±2		µA max	
DIGITAL INPUTS						
Input High Voltage, V_{INH}	2.4		2.0		V min	
Input Low Voltage, V_{INL}	0.8		0.8		V max	
Input Current, I_{INL} or I_{INH}	±1		±1		µA max	$V_{IN} = 0$ or V_{DD}
C_{IN} , Digital Input Capacitance	5		5		pF typ	
DYNAMIC CHARACTERISTICS ¹						
$t_{TRANSITION}$	200		175		ns typ	$R_L = 1 \text{ M}\Omega$, $C_L = 35 \text{ pF}$;
	300	400	220	300	ns max	$V_{S1} = \pm 10 \text{ V}$, $V_{S8} = \mp 10 \text{ V}$;
t_{OPEN}	50		90		ns typ	$R_L = 1 \text{ k}\Omega$, $C_L = 35 \text{ pF}$;
	25	10	60	40	ns min	$V_s = 5 \text{ V}$;
t_{ON} (EN)	200		180		ns typ	$R_L = 1 \text{ k}\Omega$, $C_L = 35 \text{ pF}$;
	250	400	230	300	ns max	$V_s = 5 \text{ V}$;
t_{OFF} (EN)	200		100		ns typ	$R_L = 1 \text{ k}\Omega$, $C_L = 35 \text{ pF}$;

ADG508F/ADG509F

Parameter	4" Version –40°C to +25°C +85°C		8" Version –40°C to +25°C +85°C		Unit	Test Conditions/Comments
t_{SETT} , Settling Time 0.1% 0.01%	250 400 1 2.5		130 150 1 2.5		ns max μs typ μs typ	$V_S = 5\text{ V};$ $R_L = 1\text{ kΩ}, C_L = 35\text{ pF};$ $V_S = 5\text{ V}$
Charge Injection OFF Isolation	4 68 50		15 93		pC typ dB typ	$V_S = 0\text{ V}, R_S = 0\text{ Ω}, C_L = 1\text{ nF};$ $R_L = 1\text{ kΩ}, C_L = 15\text{ pF}, f = 100\text{ kHz};$ $V_S = 7\text{ V rms};$
C_S (OFF) C_D (OFF)	5		3		pF typ	
ADG508F/ADG528F ADG509F	50 25		22 12		pF typ pF typ	
POWER REQUIREMENTS	0.1 0.1	0.2	0.05 0.1	0.2 1	mA max uA max	$V_{IN} = 0\text{ V or }5\text{ V}$

¹ Guaranteed by design, not subject to production test.

ABSOLUTE MAXIMUM RATINGS

4" Material

$T_A = +25^\circ\text{C}$ unless otherwise noted.

Table 2.

Parameter	Rating
V_{DD} to V_{SS}	44 V
V_{DD} to GND	-0.3 V to +25 V
V_{SS} to GND	+0.3 V to -25 V
Digital Input, EN, Ax	-0.3 V to $V_{DD} + 2$ V or 20 mA, whichever occurs first
V_S , Analog Input Overvoltage with Power On	$V_{SS} - 25$ V to $V_{DD} + 40$ V
V_S , Analog Input Overvoltage with Power Off	-40 V to +55 V
Continuous Current, S or D	20 mA
Peak Current, S or D (Pulsed at 1 ms, 10% Duty Cycle Max)	40 mA
Operating Temperature Range Industrial (B Version)	-40°C to +85°C
Storage Temperature Range	-65°C to +150°C
Junction Temperature	150°C
TSSOP	
θ_{JA} , Thermal Impedance	112°C/W
Plastic Package	
θ_{JA} , Thermal Impedance	
16-Lead	117°C/W
18-Lead	110°C/W
Lead Temperature, Soldering (10 sec)	260°C
SOIC Package	
θ_{JA} , Thermal Impedance	
Narrow Body	77°C/W
Wide Body	75°C/W
Lead Temperature, Soldering	
Vapor Phase (60 sec)	215°C
Infrared (15 sec)	220°C
PLCC Package	
θ_{JA} , Thermal Impedance	90°C/W
Lead Temperature, Soldering	
Vapor Phase (60 sec)	215°C
Infrared (15 sec)	220°C

8" Material

$T_A = +25^\circ\text{C}$ unless otherwise noted.

Table 3.

Parameter	Rating
V_{DD} to V_{SS}	48 V
V_{DD} to GND	-0.3 V to +48 V
V_{SS} to GND	+0.3 V to -48 V
Digital Input, EN, Ax	-0.3 V to $V_{DD} + 2$ V or 20 mA, whichever occurs first
V_S , Analog Input Overvoltage with Power On	$V_{SS} - 25$ V to $V_{DD} + 40$ V
V_S , Analog Input Overvoltage with Power Off	-40 V to +55 V
Continuous Current, S or D	20 mA
Peak Current, S or D (Pulsed at 1 ms, 10% Duty Cycle Max)	40 mA
Operating Temperature Range Industrial (B Version)	-40°C to +85°C
Storage Temperature Range	-65°C to +150°C
Junction Temperature	150°C
TSSOP	
θ_{JA} , Thermal Impedance	112°C/W
Plastic Package	
θ_{JA} , Thermal Impedance	
16-Lead	117°C/W
18-Lead	110°C/W
Lead Temperature, Soldering (10 sec)	260°C
SOIC Package	
θ_{JA} , Thermal Impedance	
Narrow Body	77°C/W
Wide Body	75°C/W
Lead Temperature, Soldering	
Vapor Phase (60 sec)	215°C
Infrared (15 sec)	220°C
PLCC Package	
θ_{JA} , Thermal Impedance	90°C/W
Lead Temperature, Soldering	
Vapor Phase (60 sec)	215°C
Infrared (15 sec)	220°C

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TYPICAL PERFORMANCE CHARACTERISTICS

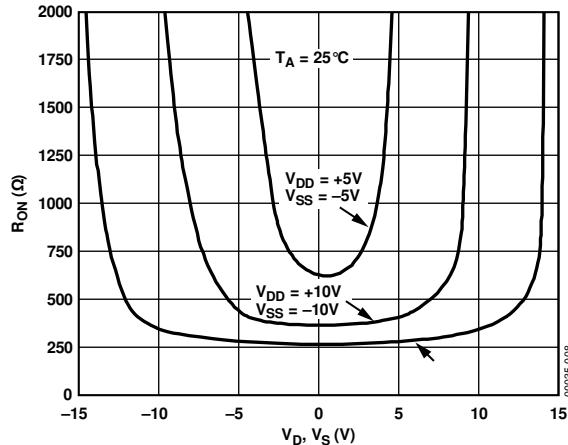


Figure 1. On Resistance as a Function of V_D (V_S) (4" Material)

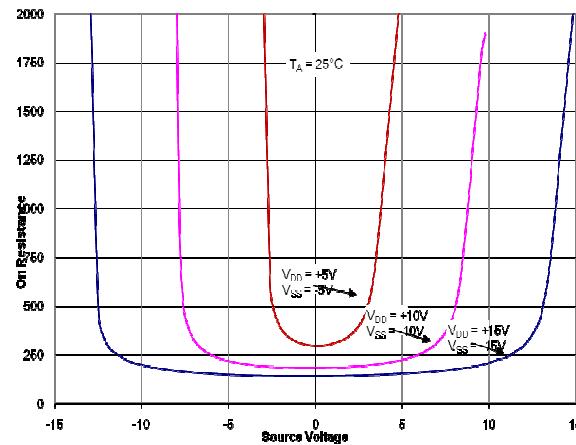


Figure 2. On Resistance as a Function of V_D (V_S) (8" Material)

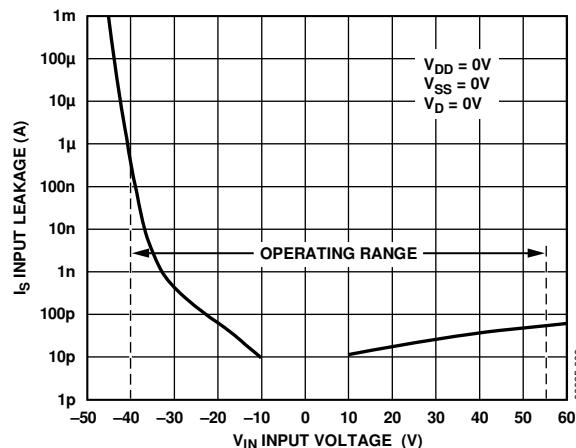


Figure 3. Input Leakage Current as a Function of V_S (Power Supplies Off) During Overtoltage Conditions (4" Material)

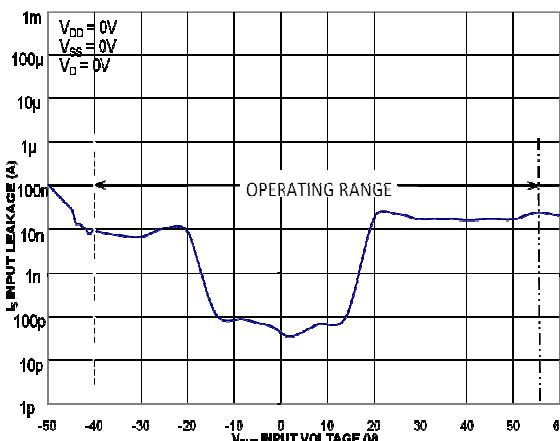


Figure 4. Input Leakage Current as a Function of V_S (Power Supplies Off) During Overtoltage Conditions (8" Material)

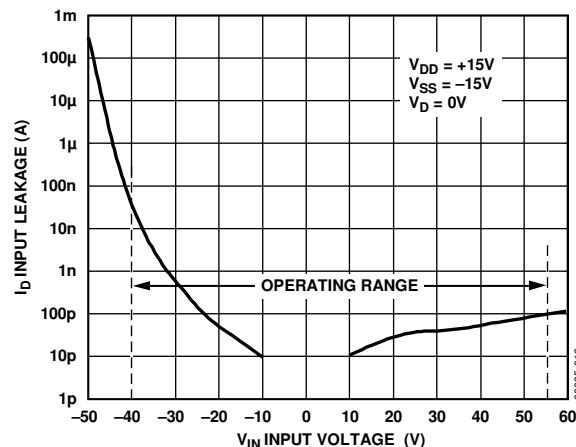


Figure 5. Output Leakage Current as a Function of V_S (Power Supplies On) During Overtoltage Conditions (4" Material)

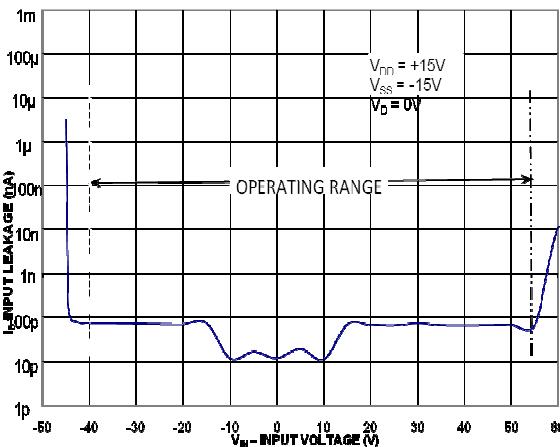


Figure 6. Output Leakage Current as a Function of V_S (Power Supplies On) During Overtoltage Conditions (8" Material)

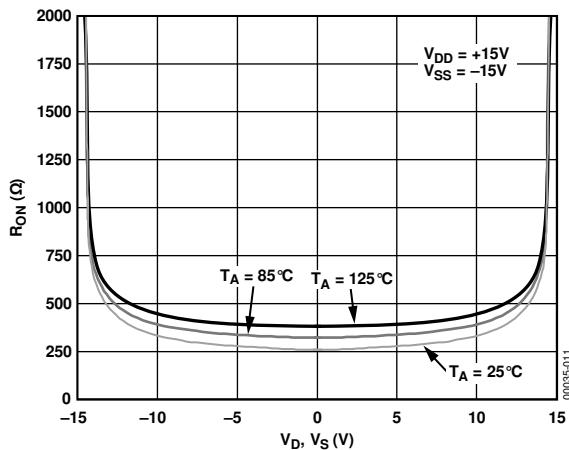


Figure 7. On Resistance as a Function of V_D (V_S) for Different Temperatures (4" Material)

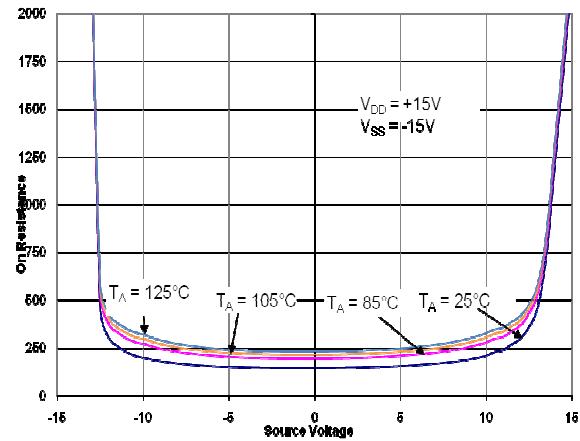


Figure 8. On Resistance as a Function of V_D (V_S) for Different Temperatures (8" Material)

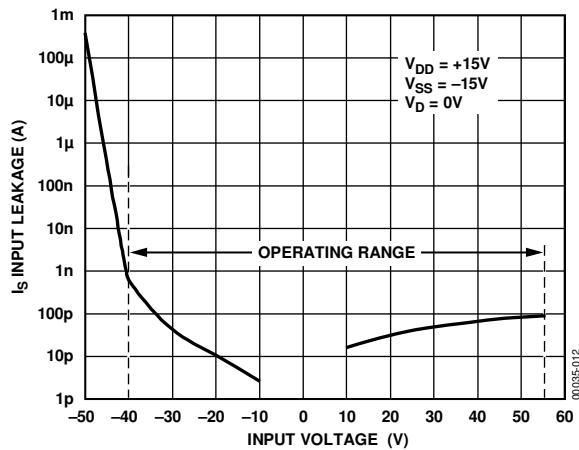


Figure 9. Input Leakage Current as a Function of V_S (Power Supplies On) During Overvoltage Conditions (4" Material)

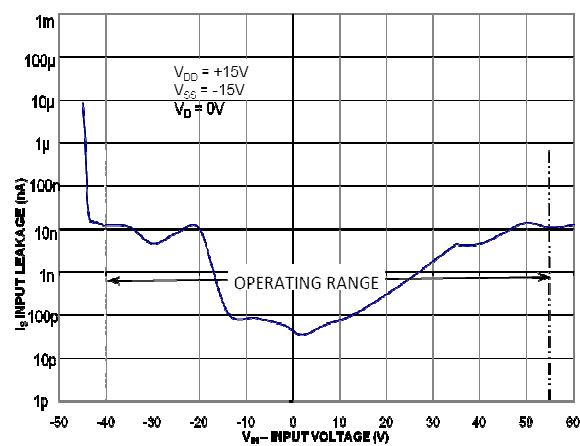


Figure 10. Input Leakage Current as a Function of V_S (Power Supplies On) During Overvoltage Conditions (8" Material)

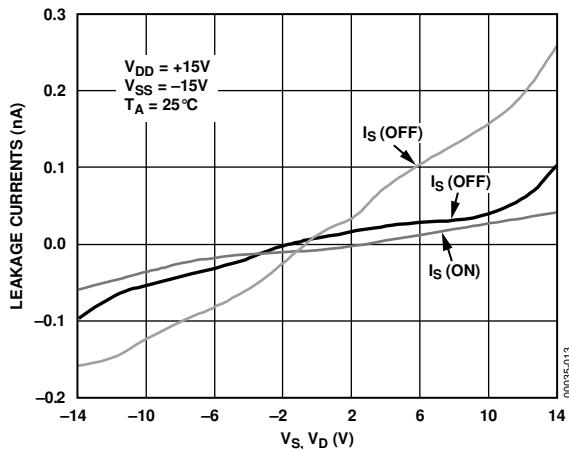


Figure 11. Leakage Currents as a Function of V_D (V_S) (4" Material)

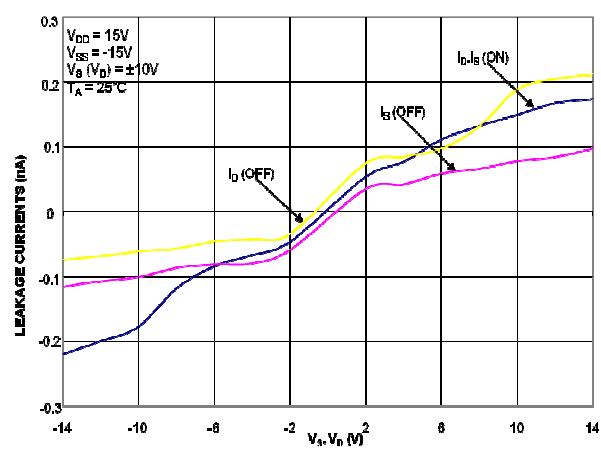
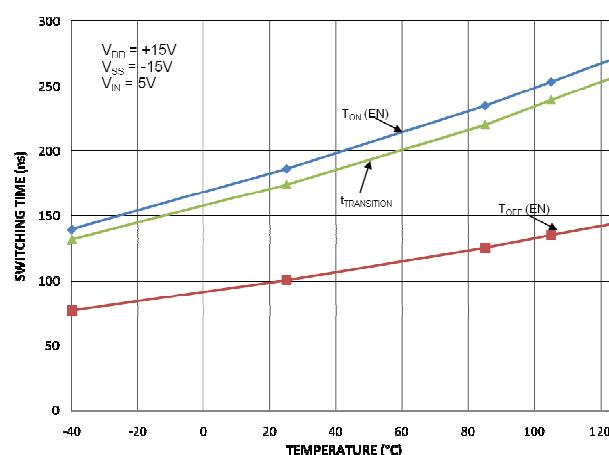
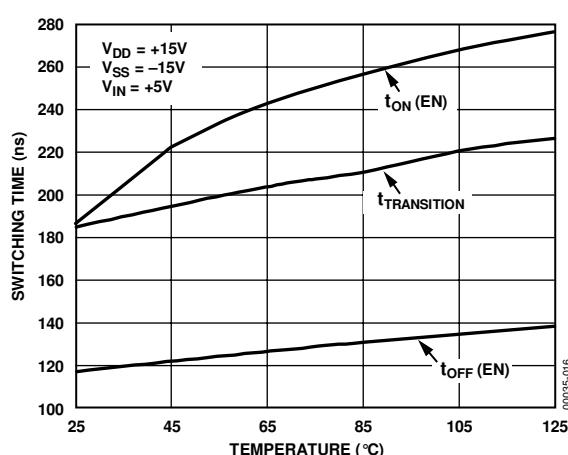
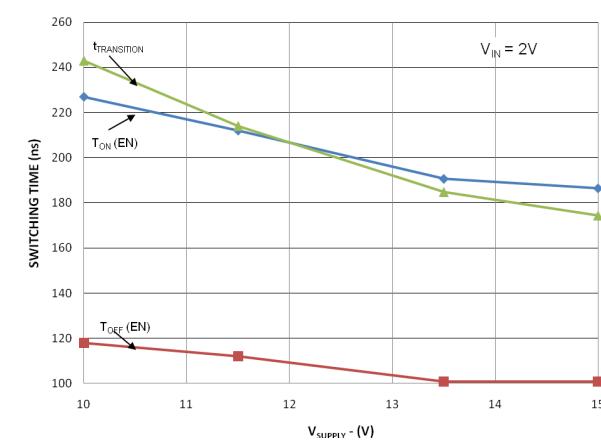
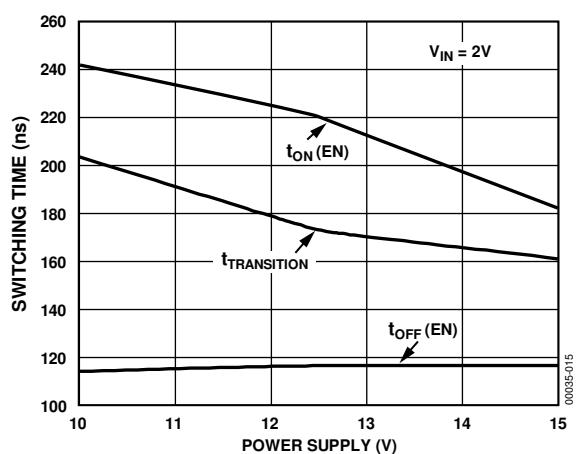
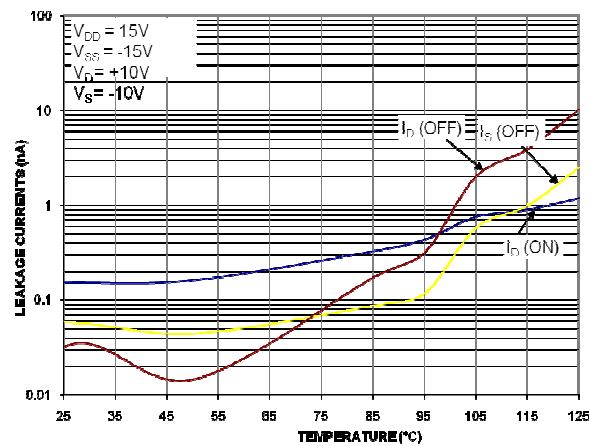
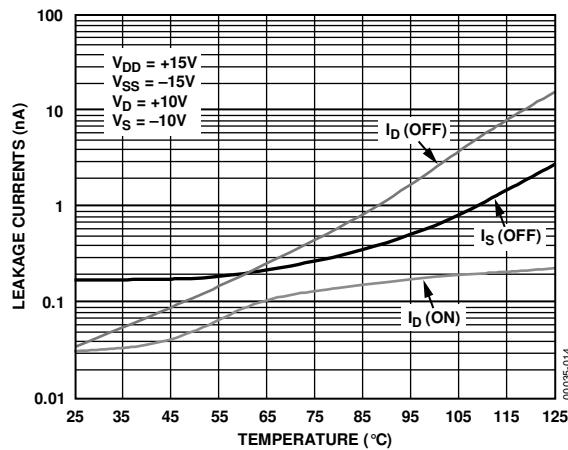


Figure 12. Leakage Currents as a Function of V_D (V_S) (8" Material)

ADG508F/ADG509F



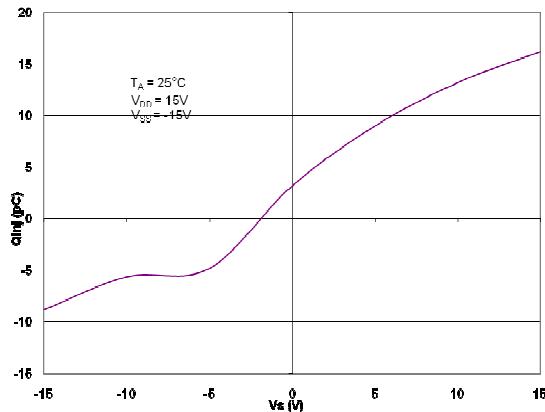


Figure 19. Charge injection (4" Material)

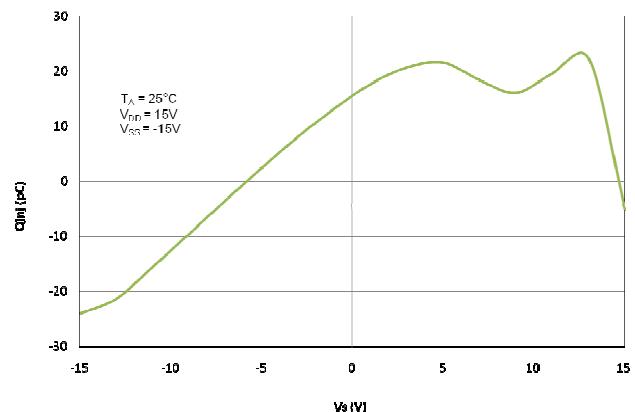


Figure 20. Charge Injection (8" Material)

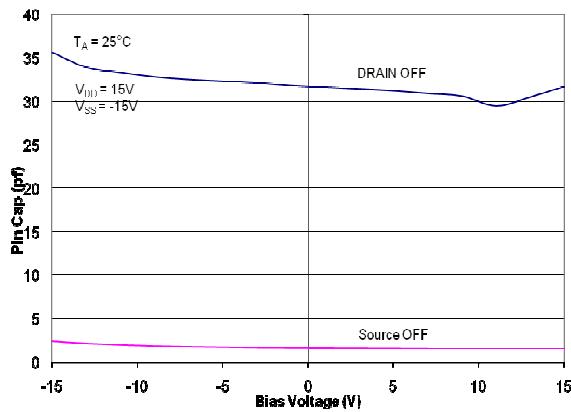


Figure 21. Capacitance Vs Source voltage (4" Material)

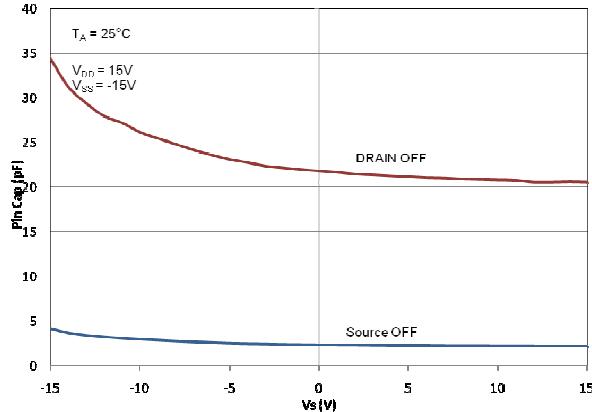


Figure 22. Capacitance Vs Source voltage (8" Material)

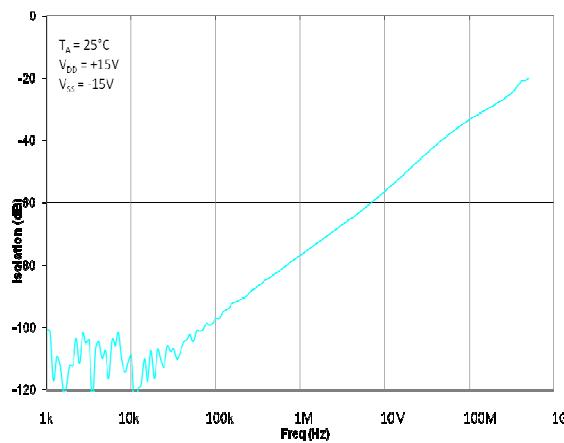


Figure 23. Off Isolation vs. Frequency (4" Material)

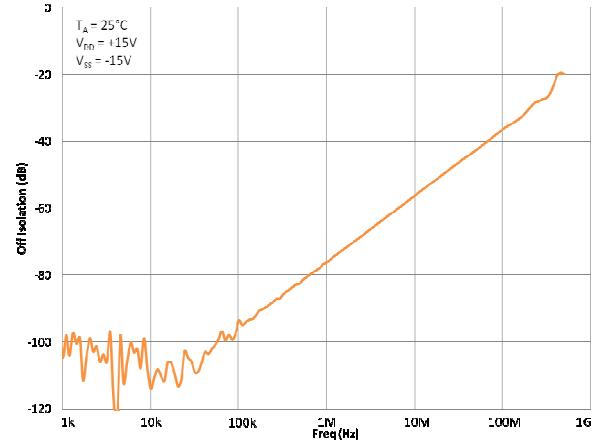


Figure 24. Off Isolation vs. Frequency (8" Material)